

IEEE Std 488.1™-2003
(Revision of
IEEE Std 488.1-1987)

Errata to IEEE Standard for Higher Performance Protocol for the Standard Digital Interface for Programmable Instrumentation

Sponsor

**Technical Committee on Automated Test Systems
and Instrumentation (TC-8)**

of the

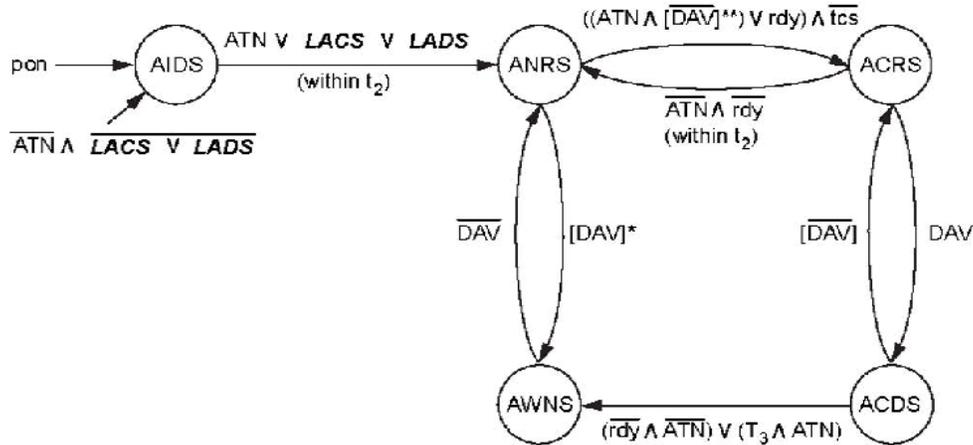
IEEE Instrumentation and Measurement Society

Correction Sheet
Issued 6 July 2015

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Page 24, Figure 5 graphic is incorrect as it mistakenly duplicates Figure 7. The Figure 5 graphic should be replaced with the following:



- * This function will never occur under normal interface operation; however, it may be implemented to simplify the interface function design.
- ** The need for the optional DAV term arises only for devices exiting AIDS and then only under take control synchronous (tcs) conditions (see 2.12.3.7). A minor revision to the controller function is under consideration that eliminates the need for the $[DAV]$ term. This term is retained for historical and compatibility reasons.

The addition of $[DAV]$ prevents a data byte from being misinterpreted as an interface message (due to momentary coincidence of DAV and ATN) when ANRS is entered from AIDS. If ANRS has been active for more than 1.5 μ s, it can be assumed DAV is false.

Figure 5—AH state diagram

Page 24, Figure 6 caption is incorrect and should be replaced with the following:

Figure 6 —AHE state diagram

Following is archival errata for IEEE Std 488.1

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Page 24, **Figure 5—AH state diagram** is incorrect; it should be replaced with the following:

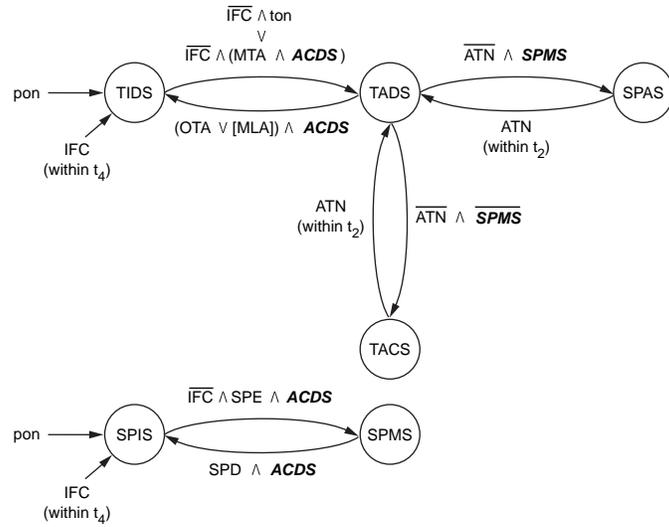


Figure 5—AH state diagram